## Development of SiC static induction transistors (SiC–SITs) with ultra–low power loss

A SiC-static induction transistors (SiC-SITs) with buried p+ gate regions by using hexagonal silicon carbide (4H-SiC) has been fabricated. The new SiC-SIT has breakdown voltage  $V_{BR}$  700 V and specific on-resistance  $R_{onS}$  1.01 m $\Omega$ ·cm<sup>2</sup>, which is the smallest  $R_{onS}$  in the world for switching devices of  $V_{BR}$  600 V~1.2 kV class. The SiC-SIT will reduce power loss extensively to 1/12 that of silicon insulated gate bipolar transistor (Si-IGBT).





Yasunori Tanaka Power Electronics Research Center

E-mail: yasunori-tanaka@aist.go.jp

AIST Today Vol.5, No.6 (2005) p.34-35 Fig 1: A schematic diagram of newly developed buried gate type SiC-SIT.

Fig 2: A voltage-current curve of newly developed buried gate type SiC-SIT.

Metrology and Measurement Technology

## Development of a new calorimeter for accurate absolute calibraiton of laser energy

In order to establish a national standard of laser energy for single laser pulses, we have developed a calibration system for laser energy meters used in industry. A reference calorimeter for measuring the absolute laser energy is composed of Bismuth Telluride semiconductor-based thermocouples and a high absorption optical cavity. To calibrate the sensitivity of devices under the test, we have adopted a simultaneous measurement method by splitting an optical laser pulse into two branches. Based on this measurement system, we will soon supply the energy standard.



Daiji Fukuda Metrology Institute of Japan F-mail:

d.fukuda@aist.go.jp

AIST Today Vol.5, No.6 (2005) p.36-37

Figure: Schematic drawing of the mesurement method of the absolute laser energy.